

| | Type | Hits | Search Text | DBS |
|---|------|--------|--|--|
| 1 | BRS | 4933 | ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near4 (defect\$5 or moisture or oil or particle or foreign or imperfect\$5)) near8 film | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB |
| 2 | BRS | 112541 | (((\$5sensor\$2 or \$5detect\$2) near4 (reference) or ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near4 (defect\$5 or moisture or oil or particle or foreign or imperfect\$5)) near8 film) and ((\$5sensor\$2 or \$5detect\$2) near4 (reference)) and @ad<=19991230 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB |
| 3 | BRS | 115 | ((((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near4 (defect\$5 or moisture or oil or particle or foreign or imperfect\$5)) near8 film) and ((\$5sensor\$2 or \$5detect\$2) near4 (reference)) and @ad<=19991230) not semiconductor | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB |
| 4 | BRS | 73 | | |